TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L<sup>2</sup>-π-MOSV)

# 2SJ380

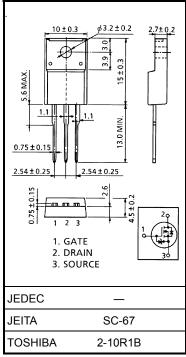
# Relay Drive, DC-DC Converter and Motor Drive Applications

- 4-V gate drive
- Low drain-source ON resistance: RDS (ON) =  $0.15 \Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 7.7 \text{ S (typ.)}$
- Low leakage current:  $IDSS = -100 \mu A \text{ (max) (VDS} = -100 \text{ V)}$
- Enhancement mode:  $V_{th} = -0.8 \sim -2.0 \text{ V (V}_{DS} = -10 \text{ V, I}_{D} = -1 \text{ mA})$

### Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	-100	V	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		V <sub>DGR</sub>	-100	V	
Gate-source voltage		$V_{GSS}$	±20	٧	
Drain current	DC (Note 1)	Ι <sub>D</sub>	-12	A	
	Pulse (Note 1)	I <sub>DP</sub>	-48	A	
Drain power dissipation (Tc = 25°C)		$P_{D}$	35	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	312	mJ	
Avalanche current		I <sub>AR</sub>	-12	Α	
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	3.5	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	

## Unit: mm



Weight: 1.9 g (typ.)

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	3.57	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD} = -25~V,~T_{ch} = 25^{\circ}C$  (initial), L = 2.94 mH, RG = 25  $\Omega,~I_{AR} = -12~A$ 

Note 3: Repetitive rating: pulse width limited by maximum junction temperature

This transistor is an electrostatic sensitive device. Please handle with caution.

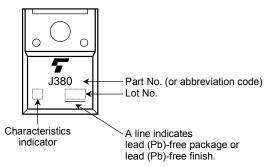
## **Electrical Characteristics (Tc = 25°C)**

Chara	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage curi	ent	I <sub>GSS</sub>	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Drain cut-off curre	ent	I <sub>DSS</sub>	$V_{DS} = -100 \text{ V}, V_{GS} = 0 \text{ V}$	_	_	-100	μΑ
Drain-source brea	kdown voltage	V (BR) DSS	$I_D = -10 \text{ mA}, V_{GS} = 0 \text{ V}$	-100	_	_	V
Gate threshold vo	ltage	V <sub>th</sub>	$V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA}$	-0.8	_	-2.0	V
Drain-source ON resistance		R <sub>DS</sub> (ON)	$V_{GS} = -4 \text{ V}, I_D = -6 \text{ A}$	_	0.25	0.32	Ω
		14DS (ON)	$V_{GS} = -10 \text{ V}, I_D = -6 \text{ A}$		0.15	0.21	
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = -10 \text{ V}, I_D = -6 \text{ A}$	4.5	7.7		S
Input capacitance		C <sub>iss</sub>		_	1100	_	pF
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	200	_	pF
Output capacitance		Coss		_	440	_	pF
Switching time	Rise time	t <sub>r</sub>	$V_{GS} = -6 \text{ A}$ $V_{OD} \approx -50 \text{ V}$ $V_{DD} \approx -50 \text{ V}$ $V_{DD} \approx -50 \text{ V}$	_	18	_	ns
	Turn-on time	t <sub>on</sub>		ĺ	30	_	
	Fall time	t <sub>f</sub>			18	_	
	Turn-off time	t <sub>off</sub>		_	65	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq -80 \text{ V}, V_{GS} = -10 \text{ V},$		48	_	nC
Gate-source charge		Q <sub>gs</sub>	$I_D = -12 A$	_	29	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>		_	19	_	nC

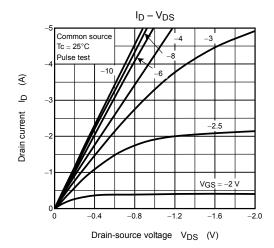
## Source-Drain Ratings and Characteristics (Tc = 25°C)

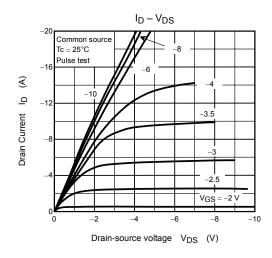
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	-12	А
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_		-48	Α
Forward voltage (diode)	V <sub>DSF</sub>	$I_{DR} = -12 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	1.7	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = -12 \text{ A}, V_{GS} = 0 \text{ V}$		160	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> /dt = 50 A/μs		0.5	_	μС

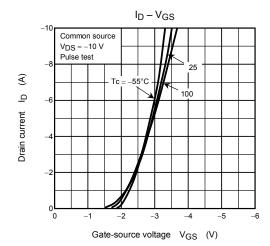
# Marking

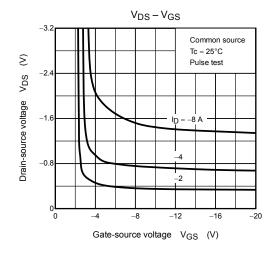


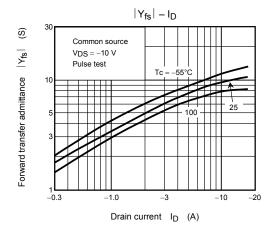
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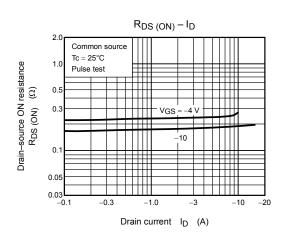


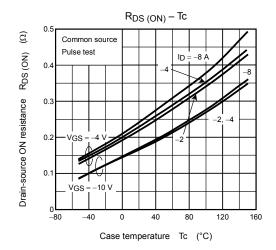


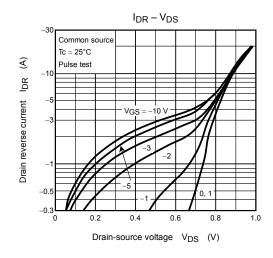


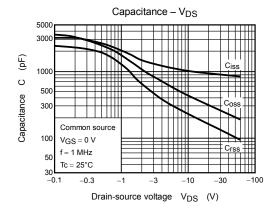


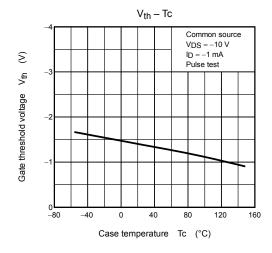


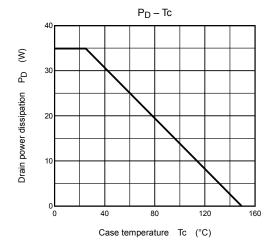


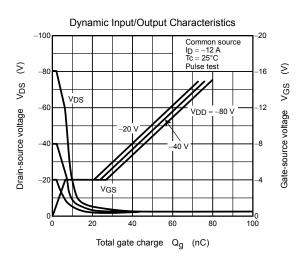




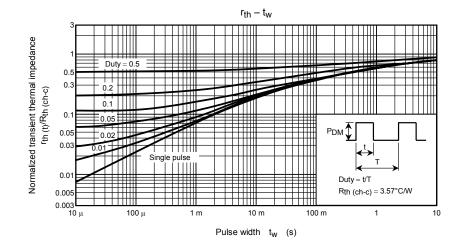


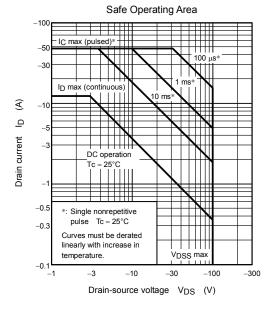


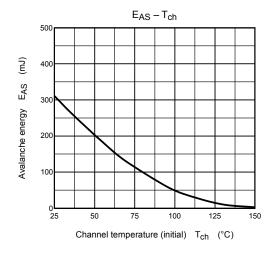


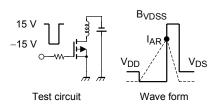


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$$\begin{aligned} R_G &= 25~\Omega \\ V_{DD} &= -25~V,~L = 2.94~mH \end{aligned} \qquad E_{AS} &= \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right) \end{aligned}$$

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